



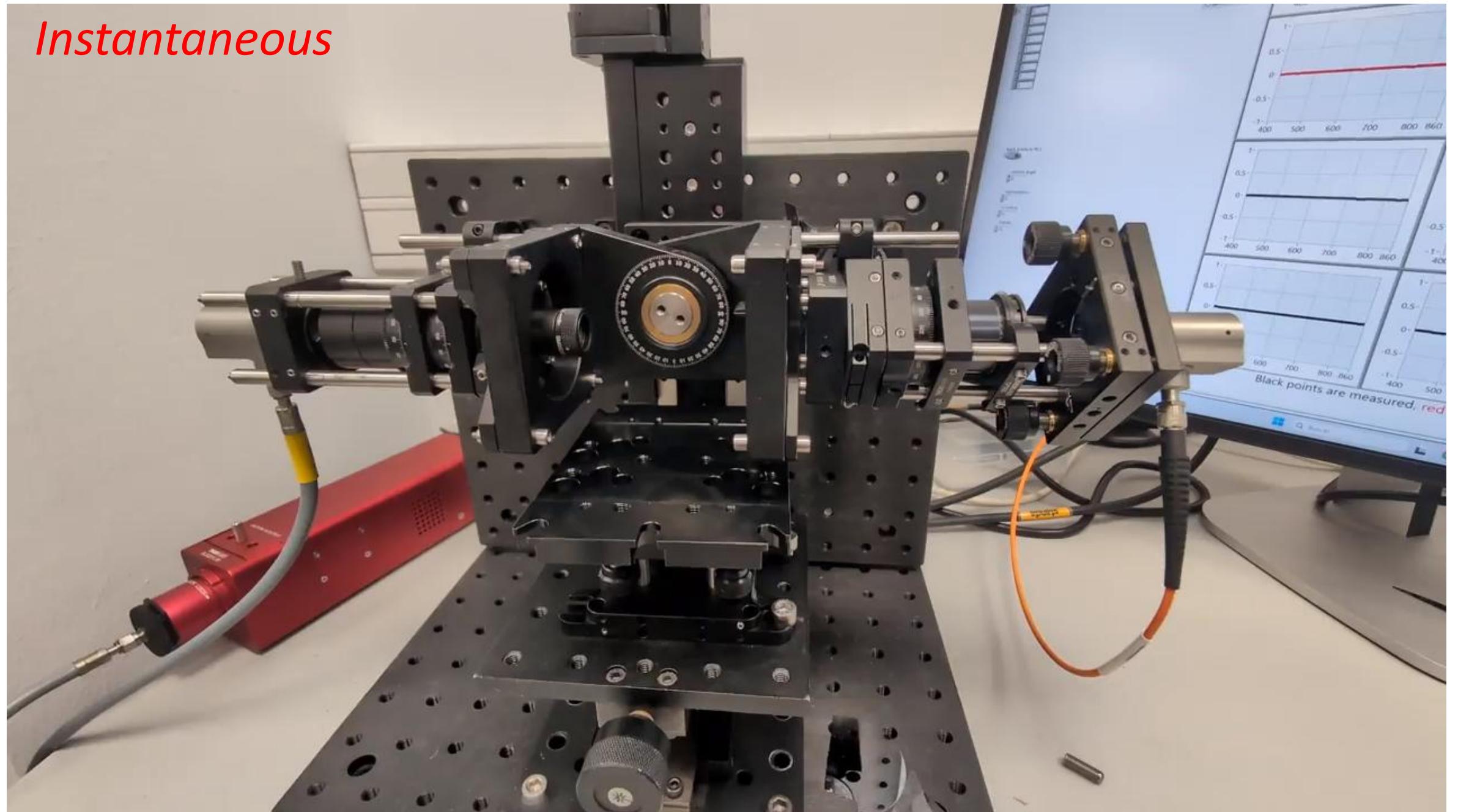
Snapshot Ellipsometer Based on Linear Algebra Demodulation

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Instantaneous



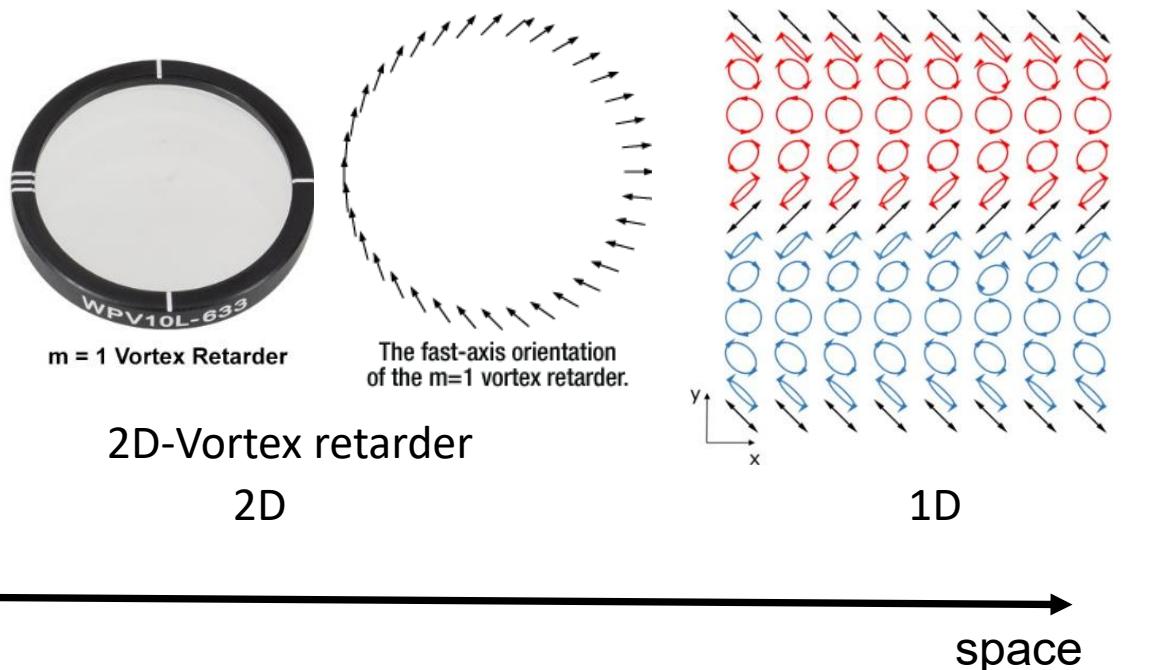
Not possible with “standard ellipsometers”
Polarization modulation in the **time domain**



Temporal response limited by the speed of motors, photoelastic modulators, liquid crystals, etc

Snapshot ellipsometers (main types)

1. Polarization modulation in spatial domain



2. Polarization modulation in *spectral domain*



- *Very non-achromatic (multi-order) crystal retarders* (this presentation)
- Interferometric module (Prof. D. Kim presentation)

Temporal response limited only by the detector

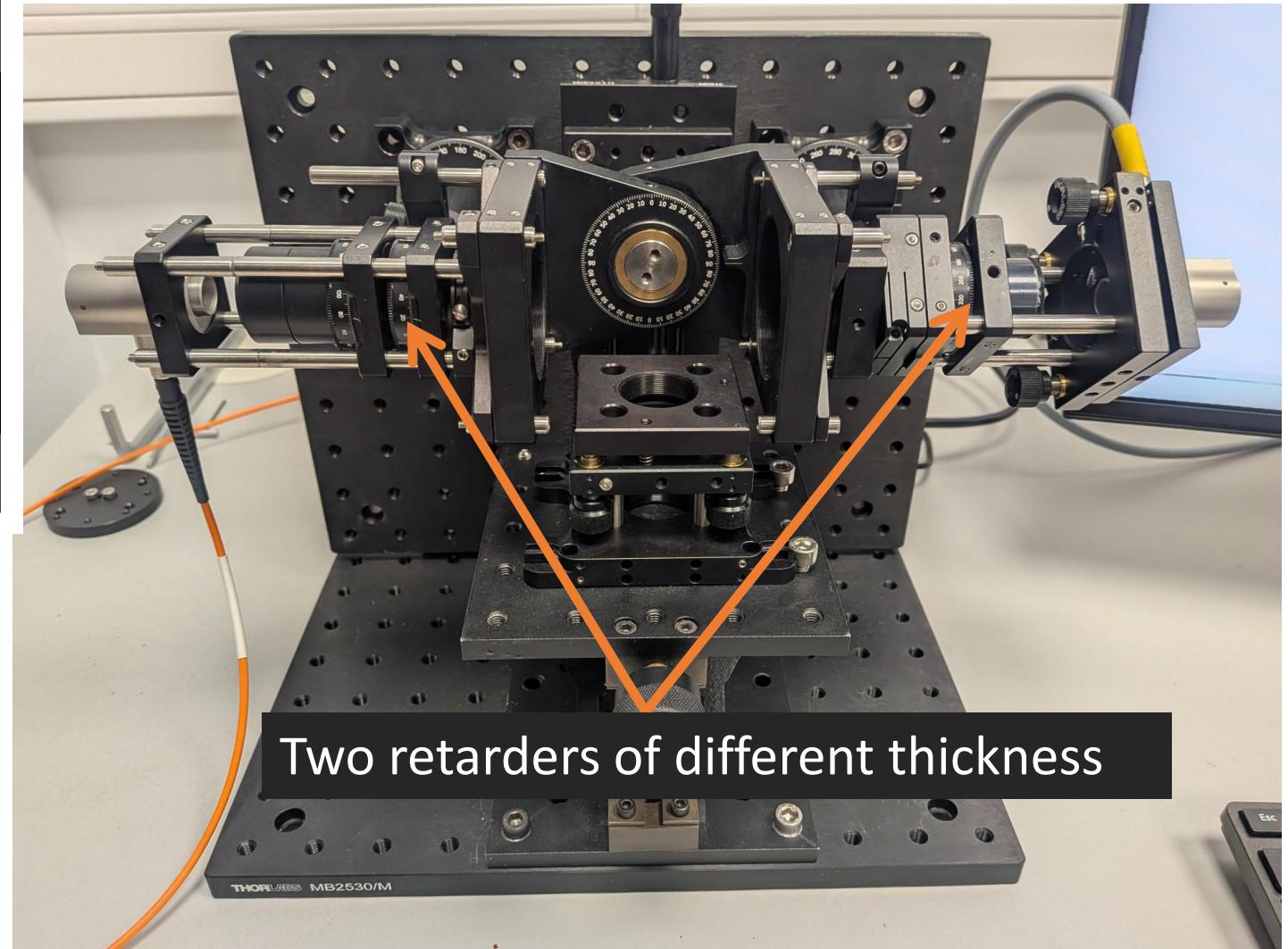
Spectral modulation → Hardware is very simple

- Multi-order crystal retarders are widely available
- High resolution 1D CMOS spectrometer

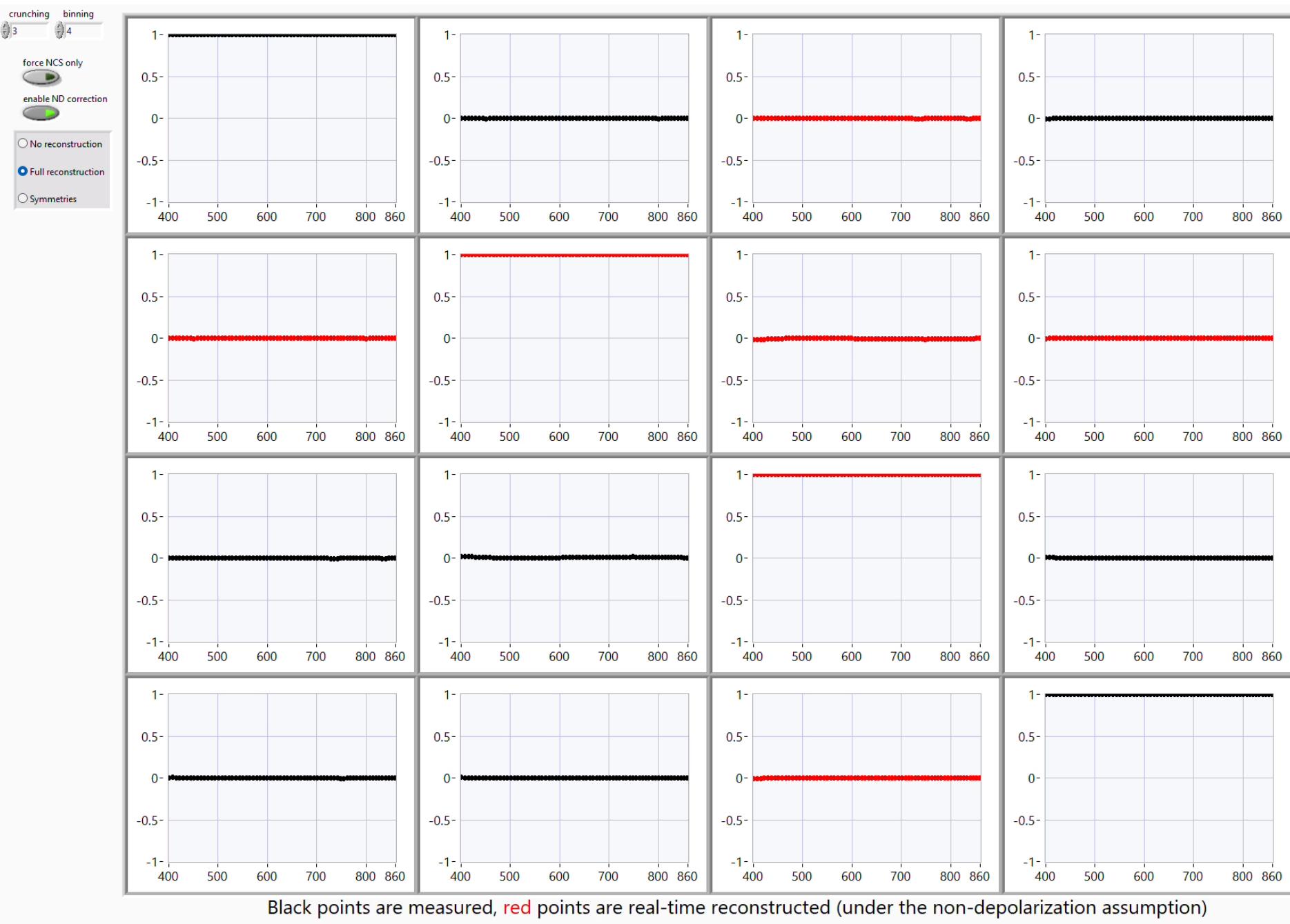
Cheap parts

$$\begin{bmatrix}
 m_{00} & m_{01} & \bullet & m_{03} \\
 \bullet & \bullet & \bullet & \bullet \\
 m_{20} & m_{21} & \bullet & m_{23} \\
 m_{30} & m_{31} & \bullet & m_{33}
 \end{bmatrix}$$

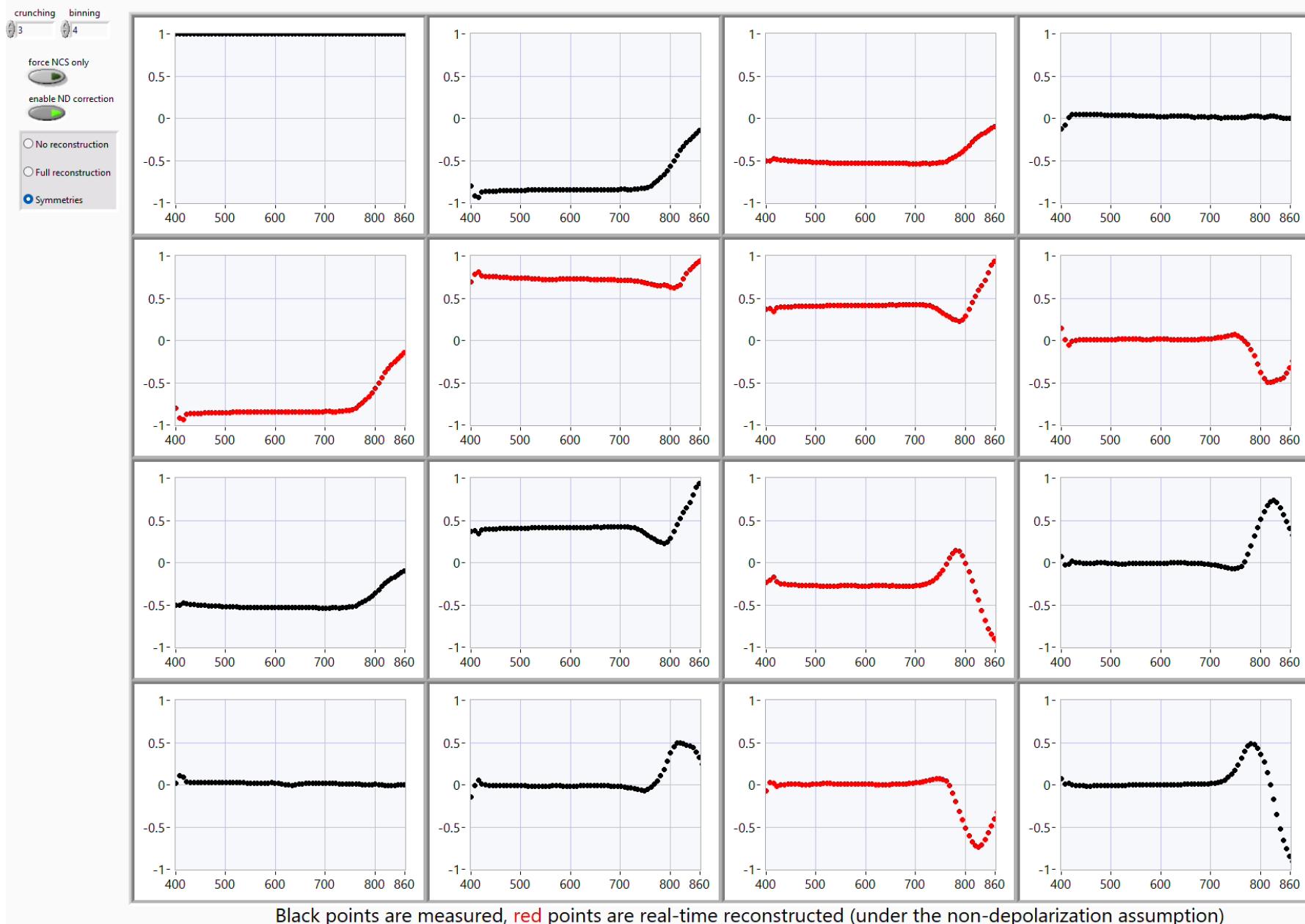
In this presentation I show reconstructed elements with the method in
R. Ossikovski and O. Arteaga, "Completing Experimental Non-Depolarizing Mueller Matrix with Both a Row and a Column Missing," J. Opt. Soc. Am. A accepted (2026)



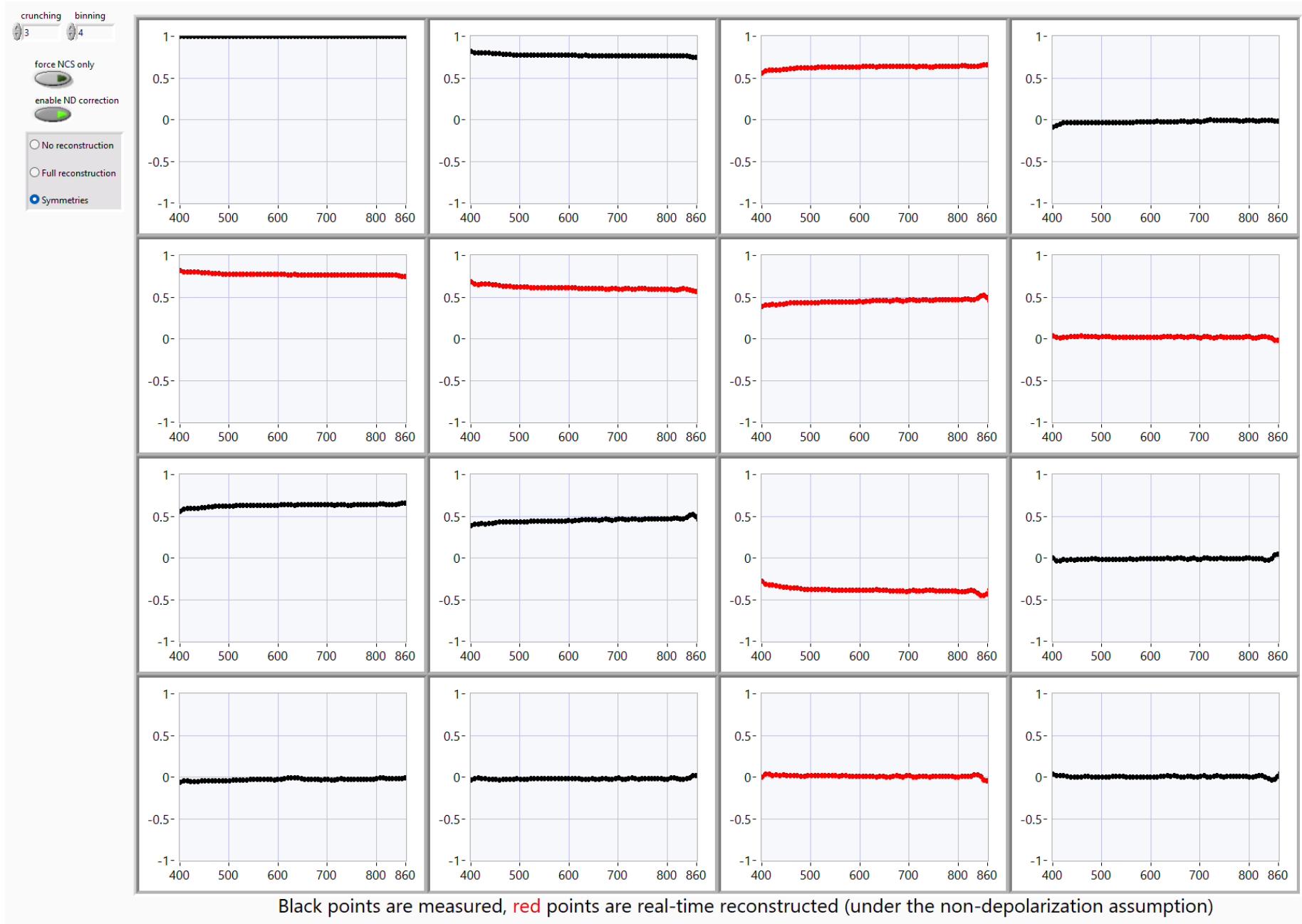
BLANK



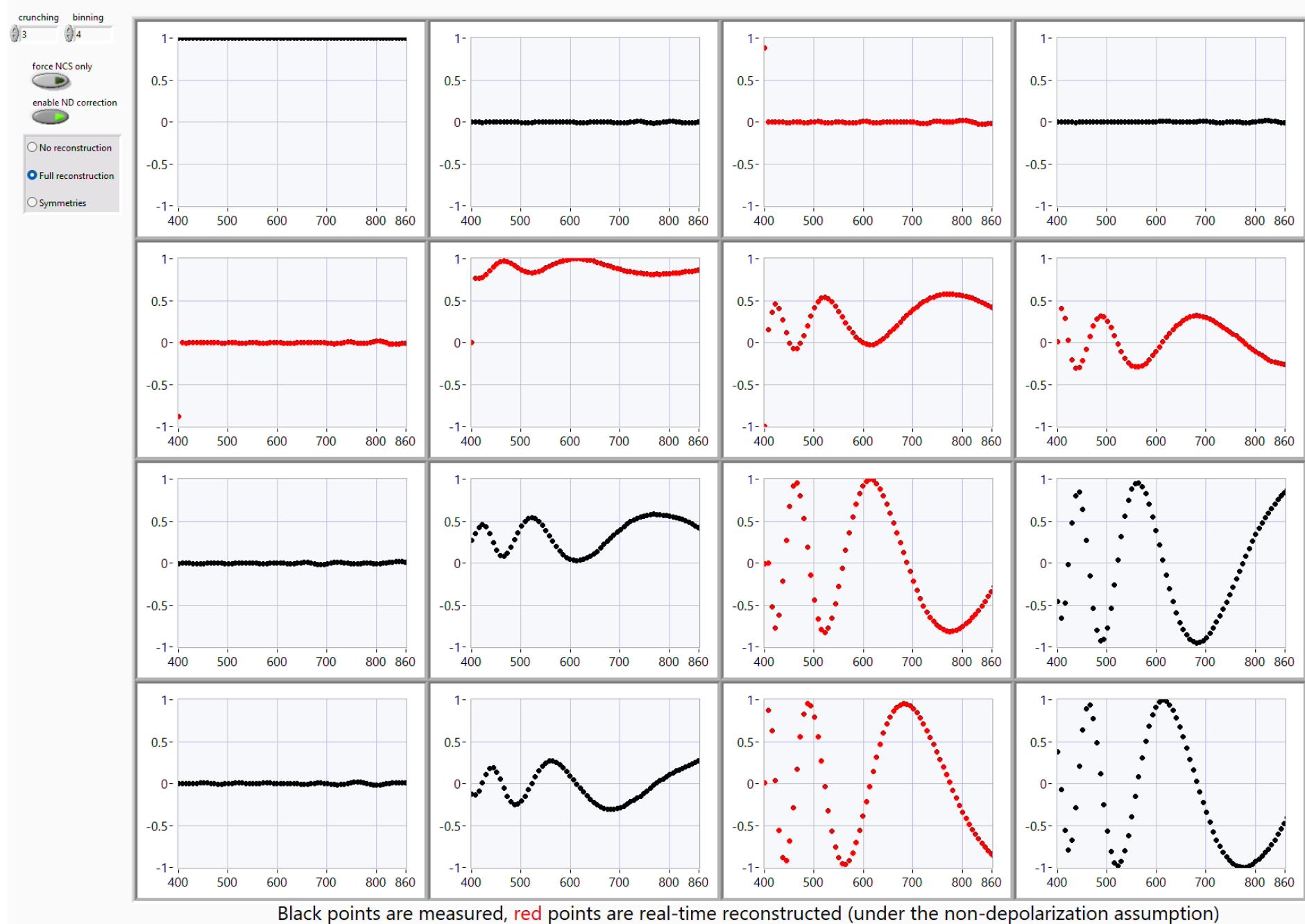
CHEAP FILM POLARIZER



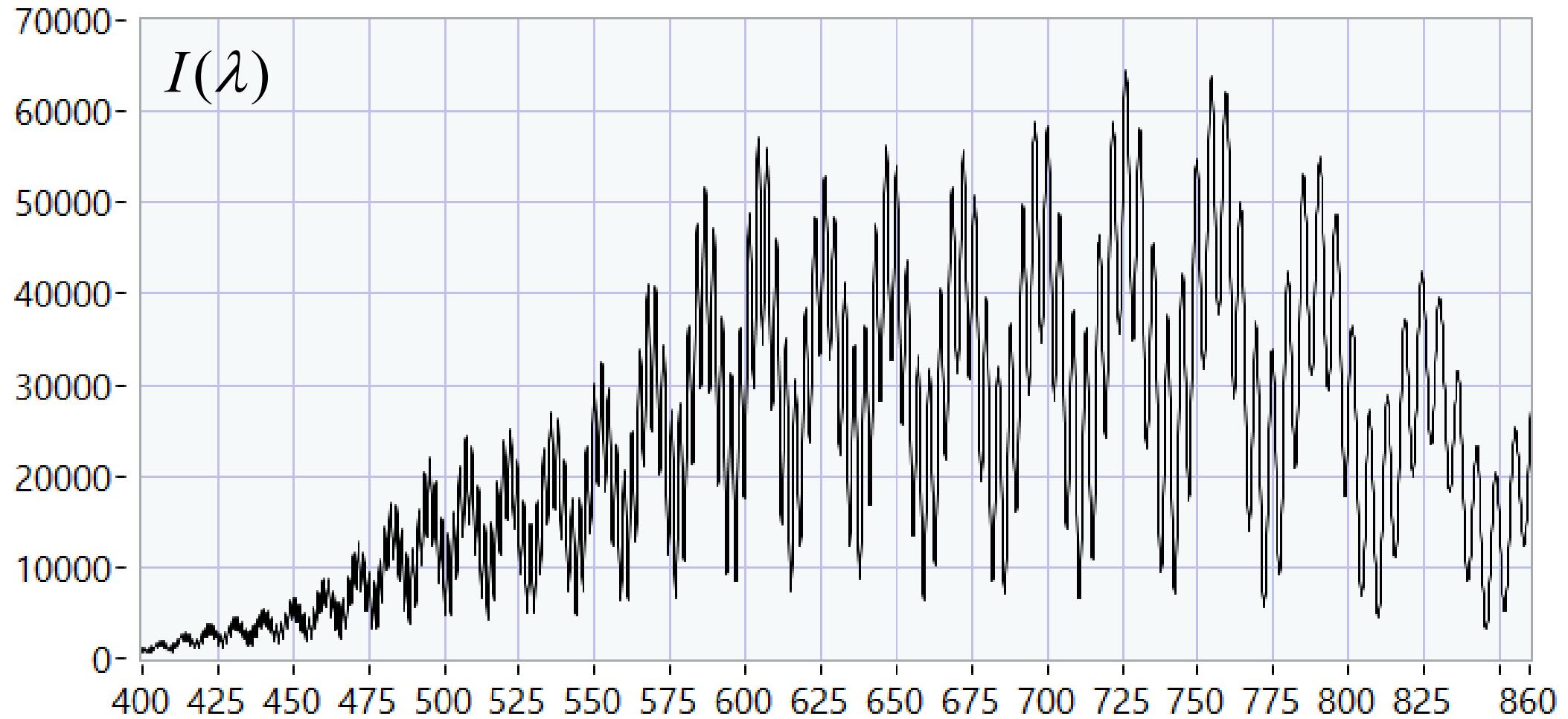
EXPENSIVE FILM POLARIZER



PLASTIC FILM



Spectral modulation → Data processing is not so simple



Noise in the data below 450nm comes from the halogen lamp (has very weak output there)

Spectral modulation → Software (data analysis) challenging

“Channeled approaches” do the data processing in **wavenumber** but have **two serious problems**:

1. Spectra are NOT periodic in wavelength and only *approximately* periodic in wavenumber

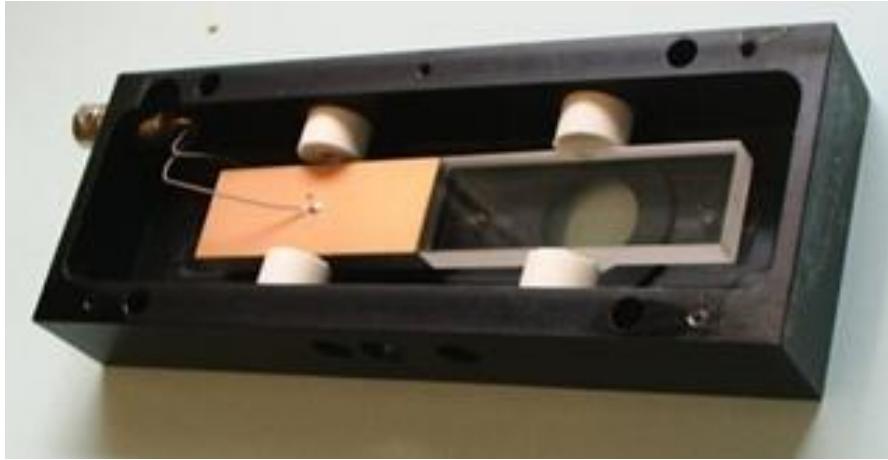
$$\delta_\lambda = \frac{2\pi\Delta n_\lambda d}{\lambda}$$

$$\Delta n_\lambda = A + \frac{B\lambda^2}{\lambda^2 - C^2} + \frac{E\lambda^2}{\lambda^2 - F^2}$$

2. Dispersive spectrometers do not provide evenly spaced data in the wavenumber domain

Spectral modulation Our Approach

Strategies we have applied for years in photoelastic modulators



A PEM changes retardance in time
Azimuth is fix



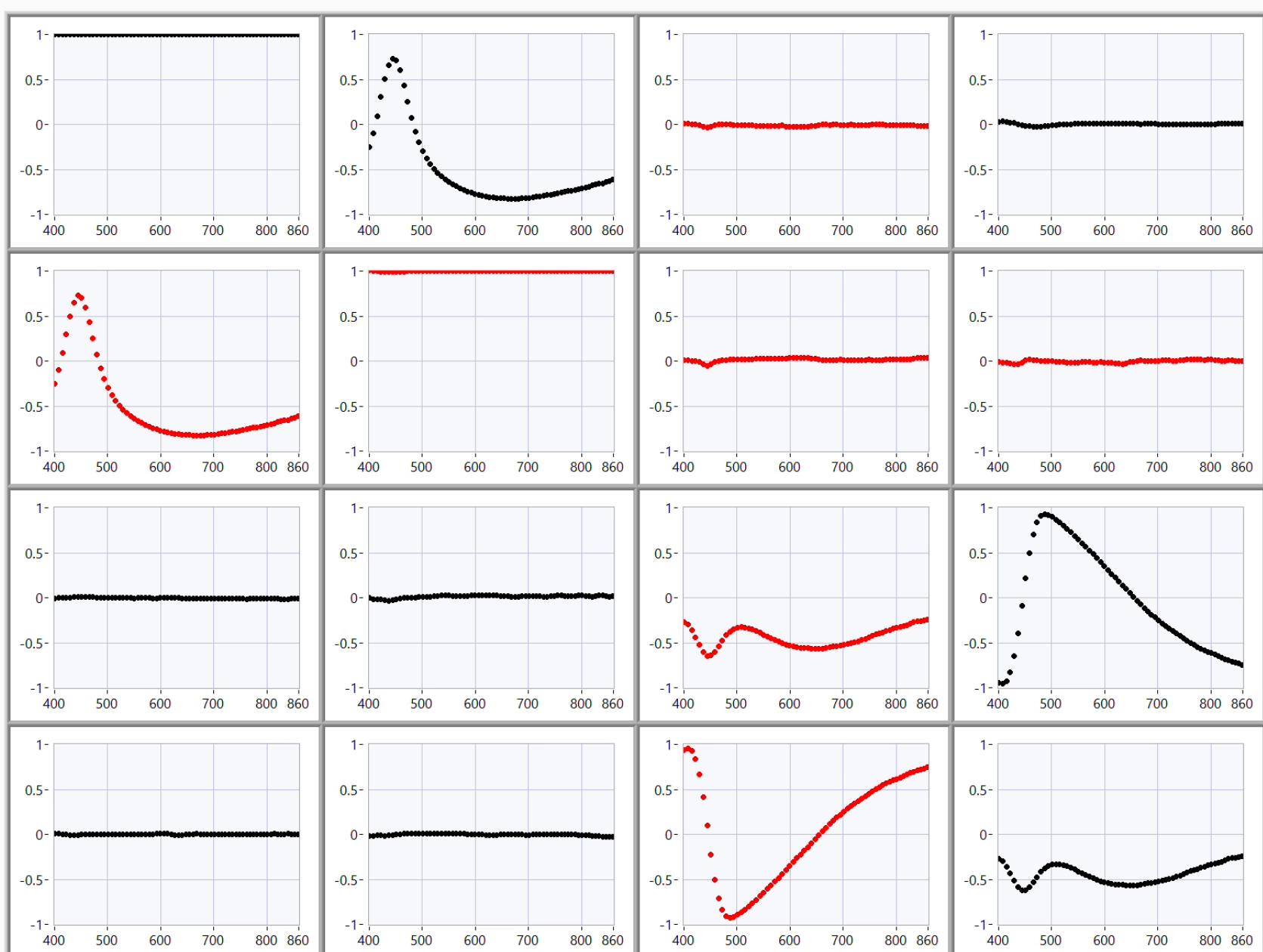
A multi-order crystal retarder changes
retardance in wavelength
Azimuth is fix

No periodicity required
Data processing based on **linear algebra**

Patent: A SNAPSHOT ELLIPSOMETRY SYSTEM AND METHOD, EP2538255

SiO₂ on Si

crunching 3 4
binning
force NCS only
enable ND correction
No reconstruction
Full reconstruction
Symmetries

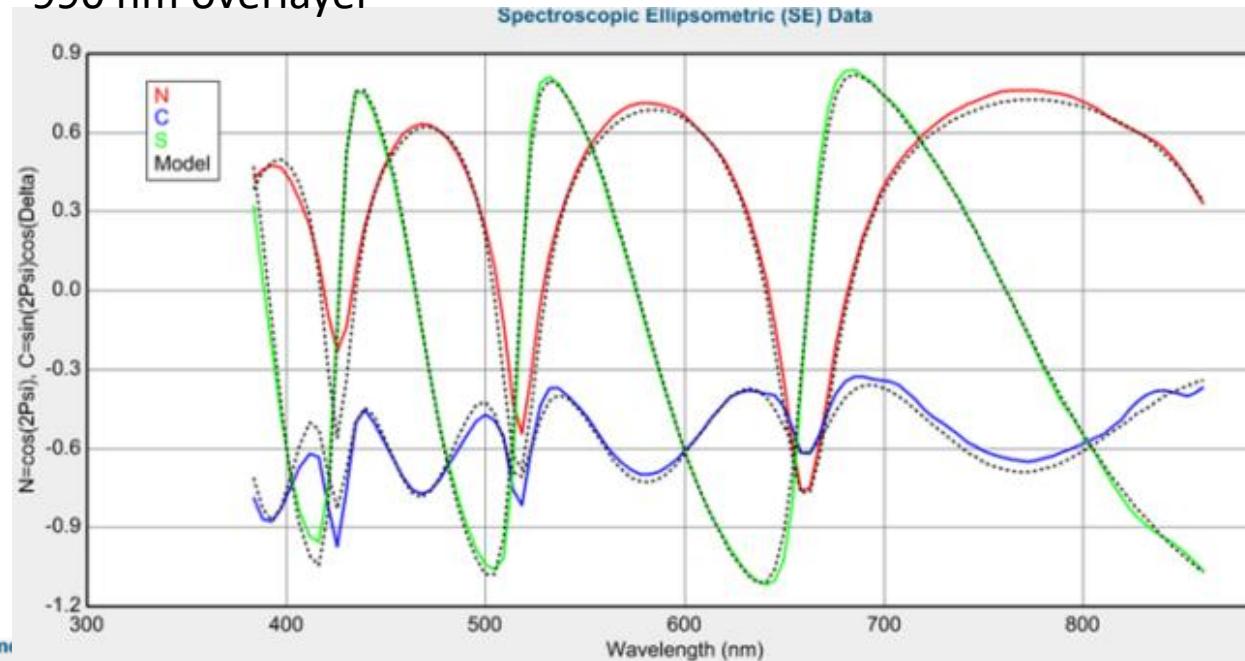
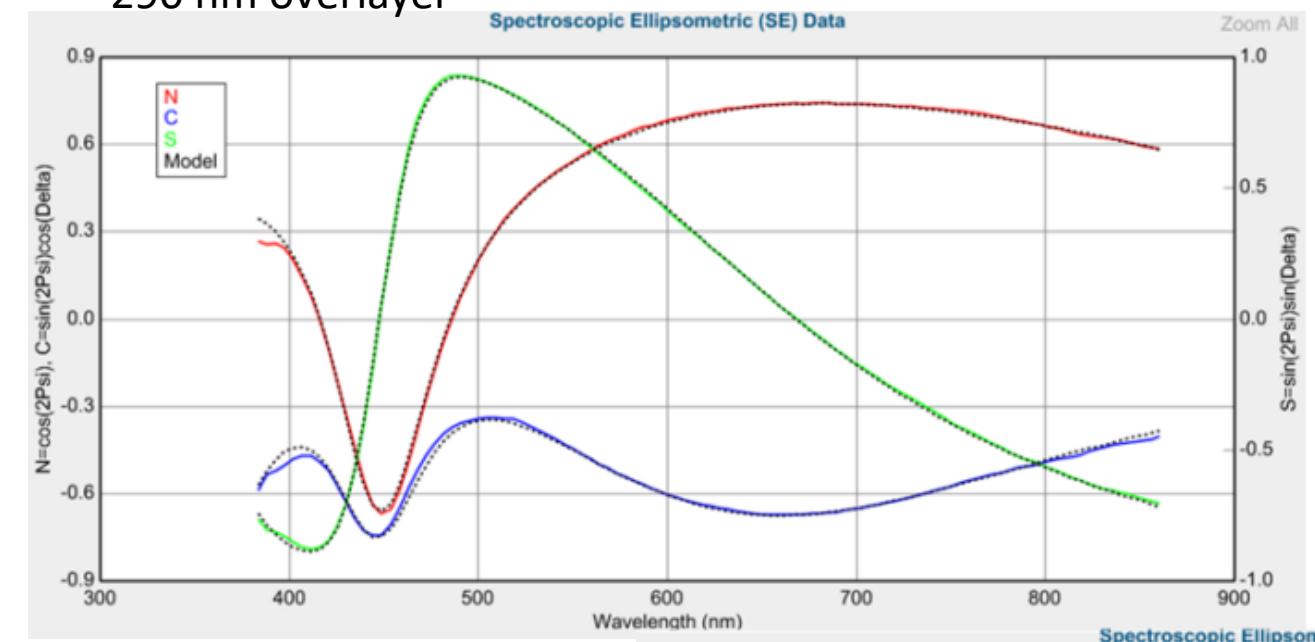


Black points are measured, red points are real-time reconstructed (under the non-depolarization assumption)

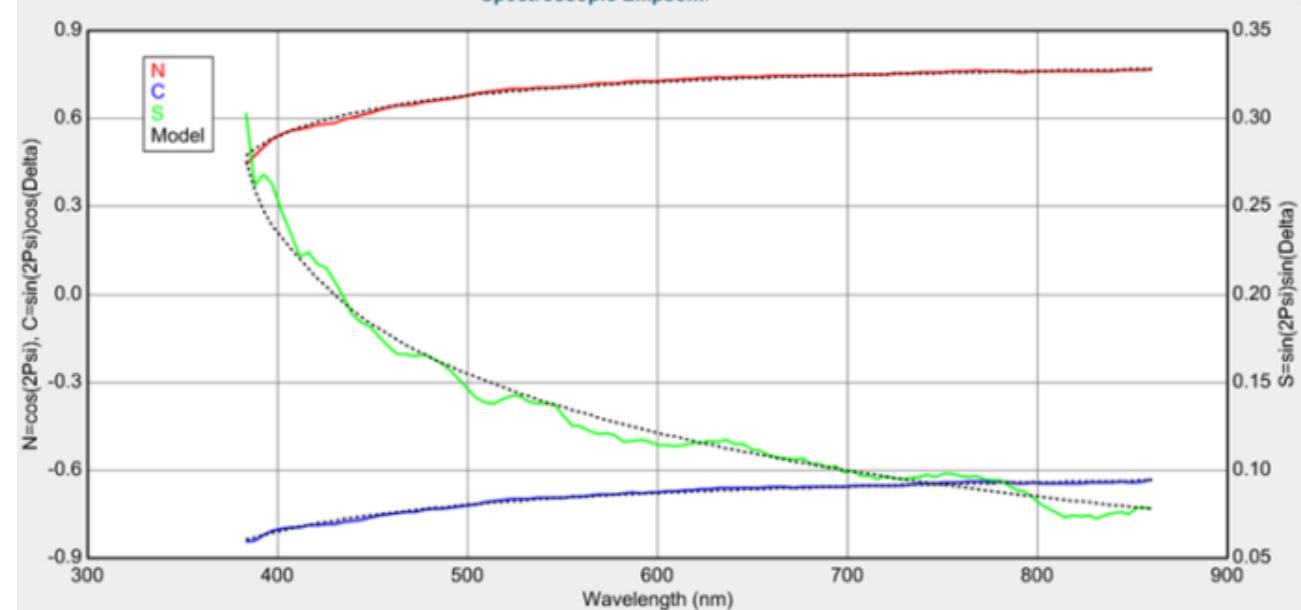
SiO_2 on Si (Fits on Woollam's CompleteEase. Prototype=> WVASE=> CompleteEase)

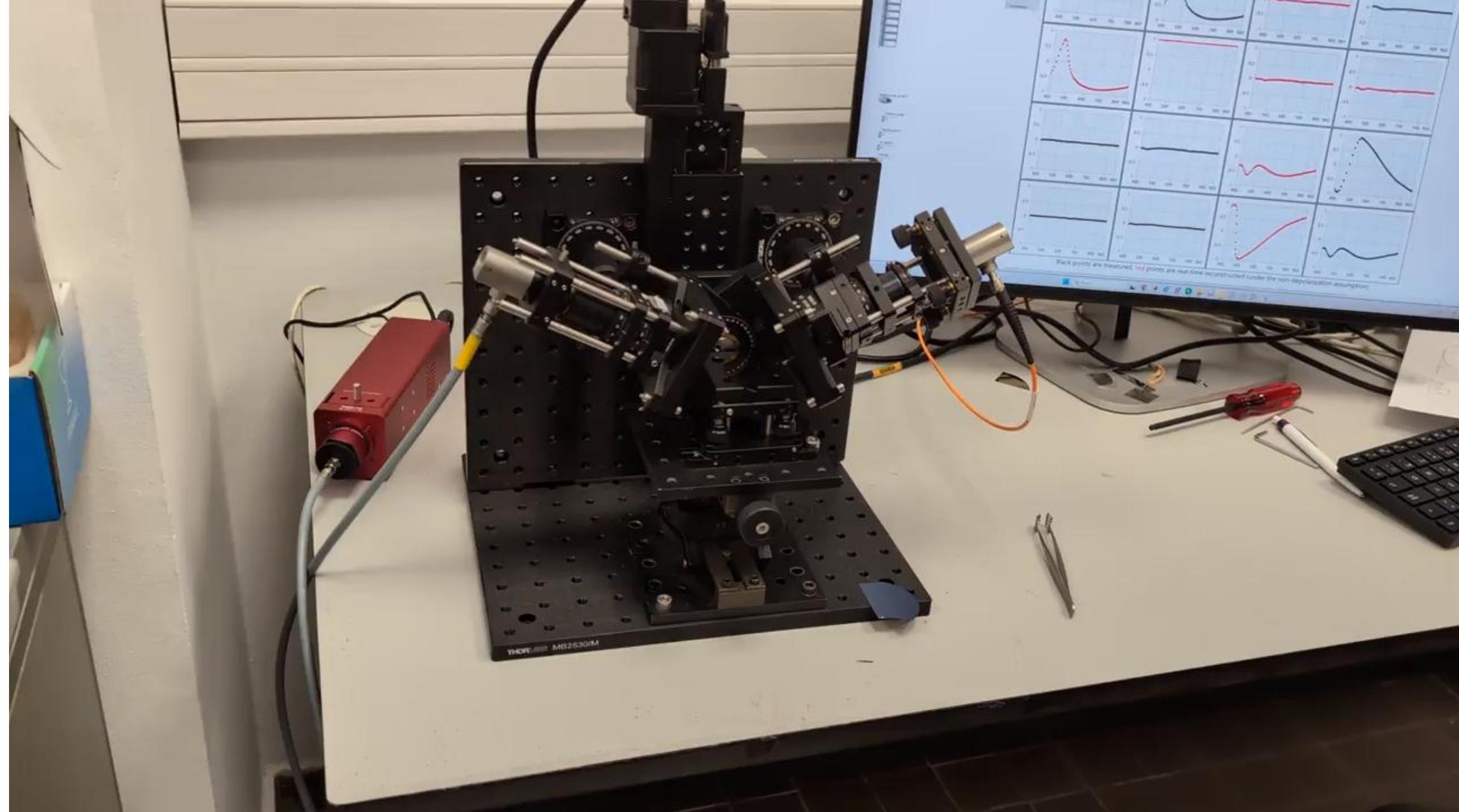
290 nm overlayer

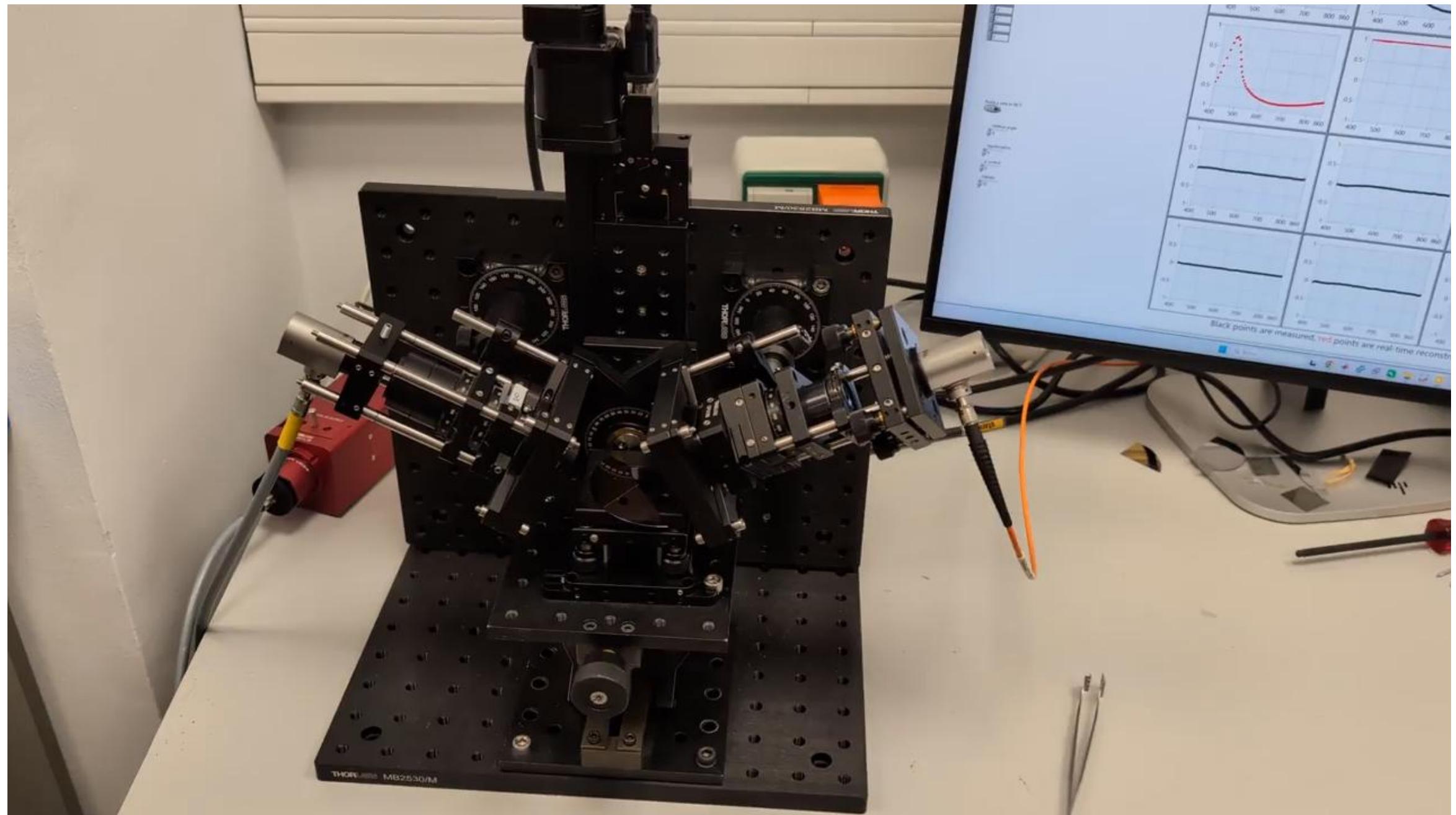
990 nm overlayer



Native oxide







Good

- Instantaneous!
- Simple & small hardware
- Highest mechanical stability
- Small random errors
- New applications:
 - Quick ellipsometric imaging by rastering (seconds instead hours)
 - Ultrafast measurements if combined with pulsed LEDs or in pump-probe experiments

Not-So-Good

- Limited spectral resolution
- **Caution with Systematic errors** (in samples with sharp spectral features)

Acknowledgements

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<http://ub.edu/plat>
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Thank you for your attention